

Adaptive Probability of Failure Estimation with Gaussian Processes

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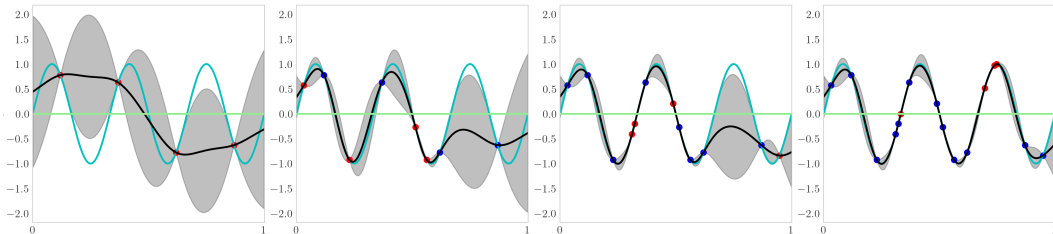
Background

Goal Estimate a **small** probability of failure to desired error tolerance

Failure A **expensive** simulation exceeds a threshold

Uses Reliability certification, structural design, power grids

Method **Iteratively** update a **Gaussian Process** [6] with **intelligent sampling** [2], similar to Bayesian Optimization [4] or Level Set Estimation [7]



Formulation

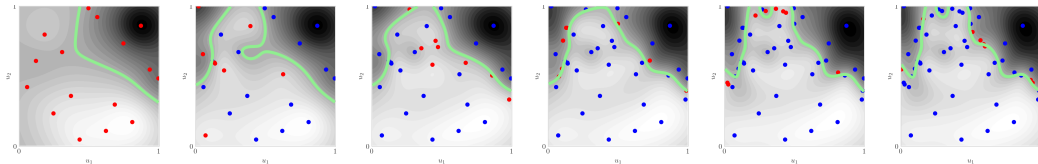
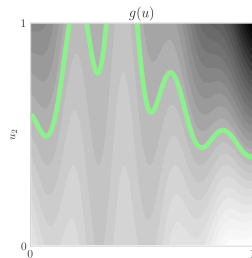
Distribution $U \stackrel{\mathbb{U}}{\sim} \mathcal{U}[0,1]^d$

Model GP G with distribution \mathbb{P}

Simulation $g : [0,1]^d \rightarrow \mathbb{R}$, path of G

Failure Region $F = \{u \in [0,1]^d : g(u) \geq 0\}$

Failure Probability $P = \mathbb{U}(F) = \mathbb{E}_{\mathbb{U}}[1_F(U)]$,
random variable in G



GP Regression i.e. Kriging

Simulated Data $\mathbf{X} \in [0, 1]^{n \times d}$, $\mathbf{Y} = g(\mathbf{X})$

Prior Covariance Kernel $k : (0, 1)^{n_1 \times d} \times (0, 1)^{n_2 \times d} \rightarrow \mathbb{R}^{n_1 \times n_2}$

Posterior Mean $m_n(u) = k(u, \mathbf{X}) K_{\mathbf{X}, \mathbf{X}}^{-1} \mathbf{Y}$, $K_{\mathbf{X}, \mathbf{X}} = k(\mathbf{X}, \mathbf{X})$

Posterior Covariance $k_n(u_1, u_2) = k(u_1, u_2) - k(u_1, \mathbf{X}) K_{\mathbf{X}, \mathbf{X}}^{-1} k(\mathbf{X}, u_2)$

Posterior Variance $\sigma_n^2(u) = k_n(u, u)$

Posterior Distribution at $u \in [0, 1]^d$ **with Conditional Probability** \mathbb{P}_n

$$G(u) \stackrel{\mathbb{P}_n}{\sim} \mathcal{N}(m_n(u), \sigma_n^2(u))$$

Posterior Failure Probability at $u \in [0, 1]^d$

$$p_n(u) = \mathbb{P}_n(G(u) \geq 0) = \Phi\left(\frac{m_n(x)}{\sigma_n(u)}\right)$$

Estimator & Error Bound

Posterior Failure Probability $p_n(u) = \Phi\left(\frac{m_n(u)}{\sigma_n(u)}\right)$, fixed $u \in [0, 1)^d$

Predicted Failure Region $\hat{F}_n = \{u \in [0, 1)^d : p_n(u) \geq 1/2\}$

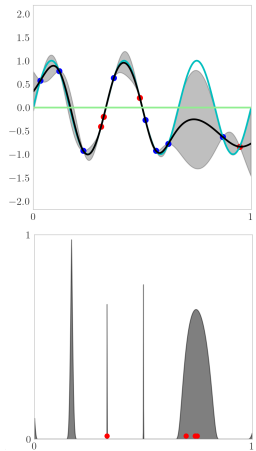
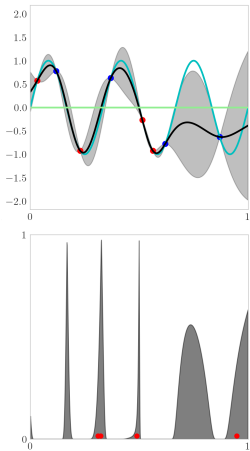
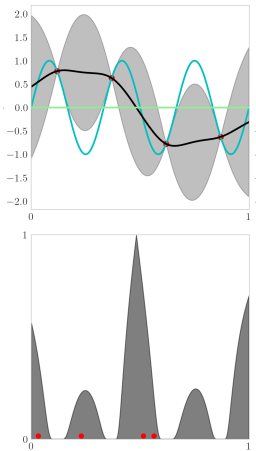
$1 - \alpha$ **Confidence Interval (CI)** $P \in [\hat{P}_n - \hat{\gamma}_n, \hat{P}_n + \hat{\gamma}_n]$ under \mathbb{P}_n

GP Based Estimate $\hat{P}_n = \mathbb{E}_{\mathbb{U}}[1_{\hat{F}_n}(U)] = \mathbb{U}(\hat{F}_n)$

GP Based CI Half-Width $\hat{\gamma}_n = \mathbb{E}_{\mathbb{U}}[\tilde{\varrho}_n(U)]/\alpha$

$$\begin{aligned}\tilde{\varrho}_n(u) &= \min\{p_n(u), 1 - p_n(u)\} \\ &= \underbrace{[1 - p_n(u)]1_{\hat{F}_n}}_{\mathbb{P}_n(\text{False Positive}(u))} + \underbrace{p_n(u)1_{\hat{F}_n^c}}_{\mathbb{P}_n(\text{False Negative}(u))}\end{aligned}$$

Expected Misclassification Rate $\tilde{\varrho}_n = \mathbb{P}_n(\text{FP}) + \mathbb{P}_n(\text{FN})$



Algorithm

1. Fix $U_0, \dots, U_{N-1} \sim \mathcal{U}[0, 1)^d$, **large** N e.g. 1 million, possible **quasi-random** design
2. Initialize $\mathbf{X} \leftarrow \emptyset, \mathbf{Y} \leftarrow \emptyset$ and set GP priors with **fixed hyperparameters**.
3. Draw $X_1, \dots, X_b \stackrel{\text{iid}}{\sim} \tilde{\varrho}_n$ using rejection sampling from the unnormalized density

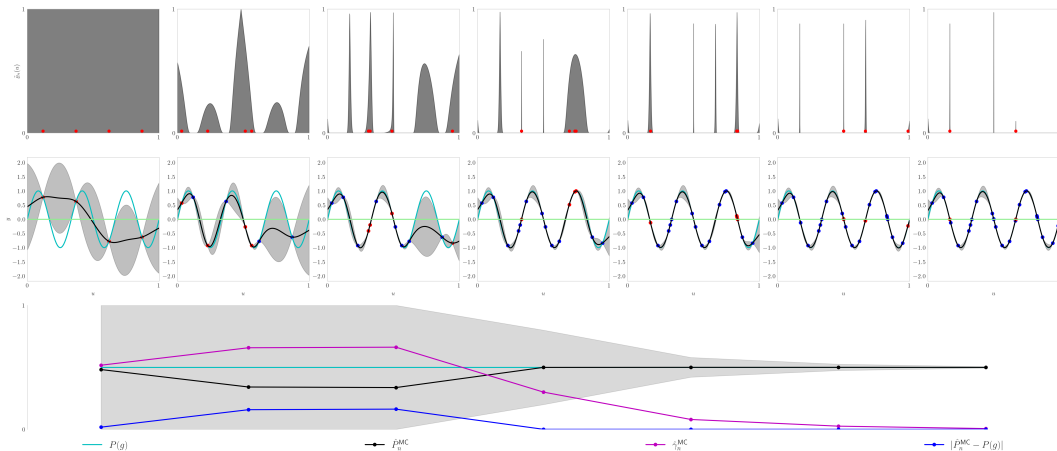
$$\tilde{\varrho}_n(u) = \min\{p_n(u), 1 - p_n(u)\} = \mathbb{P}_n(\text{FP}(u)) + \mathbb{P}_n(\text{FN}(u)).$$

4. Simulate $\tilde{\mathbf{Y}} = g(\tilde{\mathbf{X}})$ at $\tilde{\mathbf{X}} = \{X_i\}_{i=1}^b$ and update $\mathbf{X} \leftarrow \mathbf{X} \cup \tilde{\mathbf{X}}, \mathbf{Y} \leftarrow \mathbf{Y} \cup \tilde{\mathbf{Y}}$
5. Compute $\{p_n(U_i)\}_{i=0}^{N-1}$ from the GP posterior using **efficient block-matrix updates**.
6. Approximate estimate \hat{P}_n and CI half-width $\hat{\gamma}_n$ with Monte Carlo

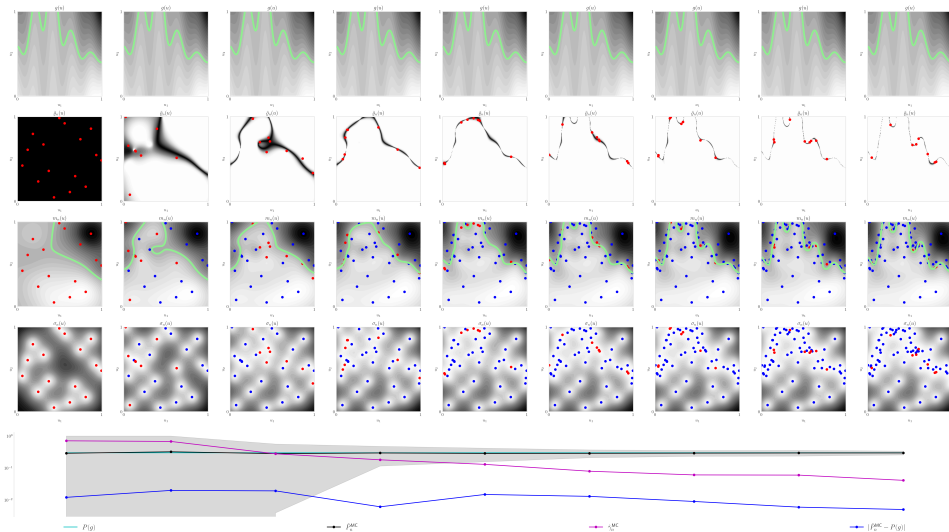
$$\hat{P}_n^{\text{MC}} = \frac{1}{N} \sum_{i=0}^{N-1} 1_{\hat{F}_n}(U_i), \quad \hat{\gamma}_n^{\text{MC}} = \frac{1}{\alpha N} \sum_{i=0}^{N-1} \tilde{\varrho}_n(U_i)$$

7. If $\hat{\gamma}_n^{\text{MC}}$ too large and sample budget *not* expired, go to step 3.
8. Return $1 - \alpha$ approximate confidence interval $[\hat{P}_n^{\text{MC}} - \hat{\gamma}_n^{\text{MC}}, \hat{P}_n^{\text{MC}} + \hat{\gamma}_n^{\text{MC}}]$

Algorithm Example: $g(u) = \sin(6\pi u)$

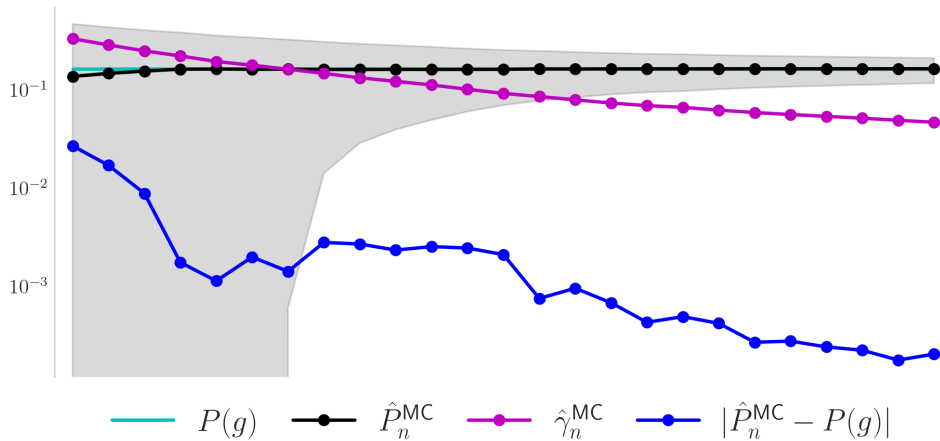


Algorithm Example: Multimodal Function [3]



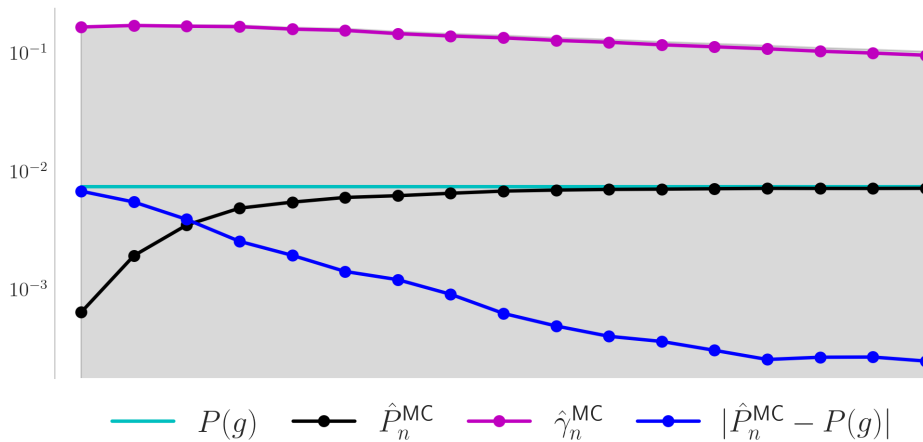
Algorithm Convergence: Ishigami function [5]

$d = 3$, $P(g) = 0.162$, **samples:** initial = 128, batch = 16, budget = 512



Algorithm Convergence: Hartmann function from BoTorch [1]

$d = 6$, $P(g) = 7.37 \times 10^{-3}$, **samples:** initial = 512, batch = 32, budget = 1024



Future Work

Implementation

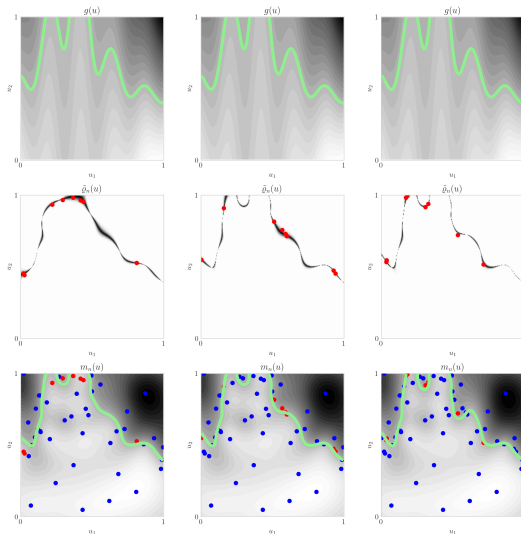
- open source
- accommodate alternative sampling schemes
- larger suite of examples

Analysis

- include uncertainty in $\hat{P}_n^{\text{MC}}, \hat{\gamma}_n^{\text{MC}}$ in CI
- convergence rate of CI width

Extensions

- multi-fidelity problems
- multi-level problems



References I

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- [4] Peter I Frazier. “Bayesian optimization”. In: *Recent advances in optimization and modeling of contemporary problems*. Informs, 2018, pp. 255–278.
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References II

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